

Program SETS March 25-29, 2013, Obergurgl / Austria

Monday, March 25

Opening Session (in the evening)

Tuesday, March 26

Session 1 : BIST and ATPG

Chair: Hans-Joachim Wunderlich - University of Stuttgart, Germany

Speaker	Title
Athanasios Dimakos - TIMA Laboratory, Grenoble, France	Built-in Test in Wireless Systems Using Non-Intrusive Sensors
Dominik Erb- Albert-Ludwigs-University, Freiburg, Germany	Accurate QFB-based Test Pattern Generation in Presence of Unknown Values and beyond
Sven Reimer - Albert-Ludwigs-University, Freiburg, Germany	Provably Optimal Test Cube Generation Using Quantified Boolean Formula Solving
Senling Wang - Kyushu Institute of Technology, Japan	A Scan-out Power Reduction Method for Logic BIST

Session 2 : Complex Systems Engineering

Chair: Bernd Becker - Albert-Ludwigs-University, Freiburg, Germany

Speaker	Title
Wenjing Rao - University of Illinois, Chicago, USA	Achieving Fairest Distribution of Resources Collectively: Complexity and Algorithms
Ruediger Ibers - University of Paderborn, Germany	Ants in NoC
Carolina Metzler - LIRMM, Montpellier, France	Ensuring Reliability of 3D-ICs
Martin Andraud - TIMA Laboratory, Grenoble, France	Towards Self-healing Integrated Circuits: Application of BIST for Auto-Adaptive RF Power Amplifiers

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Wednesday, March 27

Session 3: Signal Integrity and Security

Chair: Lorena Anghel - TIMA Laboratory, Grenoble, France

Speaker	Title
Anu Asokan - LIRMM, Montpellier, France	Signal Integrity- Aware Pattern Generation for Delay Testing
Kohei Miyase - Albert-Ludwigs-University, Freiburg, Germany	Controllability Analysis of Local Switching Activity for Layout Design
Jie Jiang - University of Passau, Germany	A mixed mode simulation of delay induced by IR-drop
Philipp Jovanovic - University of Passau, Germany	Multi-Stage Fault Attacks on Block Ciphers

Session 4: Fault Tolerance

Chair: Wenjing Rao - University of Illinois, Chicago, USA

Speaker	Title
Andreas Riefert - Albert-Ludwigs-University, Freiburg, Germany	Identification of Critical Variables using an FPGA-based Fault Injection Framework
Chang Liu - University of Stuttgart, Germany	Efficient Observation Point Selection for Hardware Aging Monitoring
Victor Tomashevich - University of Passau, Germany	Towards Fault Tolerant LTE-MIMO detectors
Viktor Froese - University of Paderborn, Germany	Robustness Checking with ATPG

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Thursday, March 28

Session 5: Analog Mixed Signal and Delay Test

Chair: Mounir Benabdenbi - TIMA Laboratory, Grenoble, France

Speaker	Title
Stéphane David-Grignot - LIRMM, Montpellier, France	Phase Noise Measurement of Sinusoid Based Signal on Digital Test Equipment for Low-Cost Testing of Analog/RF Circuits
Syhem Larguech - LIRRM, Montpellier, France	Development of technical test for analog integrated circuits
Eric Schneider - University of Stuttgart, Germany	High-performance Time-Simulation of CMOS-Circuits
Matthias Sauer - Albert-Ludwigs-University, Freiburg, Germany	Efficient SAT-Based Dynamic Compaction and Relaxation for Longest Sensitizable Paths

Session 6: Debug and Diagnosis

Chair: Seiji Kajihara -Kyushu Institute of Technology, Japan

Speaker	Title
Dominik Ull - University of Stuttgart, Germany	Software-based Diagnosis
Thomas Indlekofer - University of Paderborn, Germany	Adaptive Diagnosis for Intermittent Faults
Boyang Du - Politecnico di Torino, Italy	A New Method for Control Flow Error Detection Using Debug Interface

Session 7: FPGA and Memory Test

Chair: Sybille Hellebrand - University of Paderborn, Germany

Speaker	Title
Saif-Ur Rehmann - TIMA Laboratory, Grenoble, France	Development of a Test Time Reduction Methodology for a Novel SRAM & Cluster-based FPGA
Joao Azevedo - LIRMM, Montpellier, France	Magnetic Memory Testing from MRAM to MLU

Friday, March 29

Closing Session (in the morning)